- Member of the Texas Instruments
   Widebus+™ Family
- EPIC™ (Enhanced-Performance Implanted CMOS) Submicron Process
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- ESD Protection Exceeds JESD 22
  - 2000-V Human-Body Model (A114-A)
  - 200-V Machine Model (A115-A)
  - 1000-V Charged-Device Model (C101)
- Packaged in Plastic Fine-Pitch Ball Grid Array Package

#### description

This 32-bit noninverting bus transceiver is designed for 1.65-V to 3.6-V V<sub>CC</sub> operation.

The SN74ALVCH32245 is designed for asynchronous communication between data buses. The control-function implementation minimizes external timing requirements.

This device can be used as four 8-bit transceivers, two 16-bit transceivers, or one 32-bit transceiver. It allows data transmission from the A bus to the B bus or from the B bus to the A bus, depending on the logic level at the direction-control (DIR) input. The output-enable (OE) input can be used to disable the device so that the buses are effectively isolated.

To ensure the high-impedance state during power up or power down,  $\overline{OE}$  should be tied to  $V_{CC}$  through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

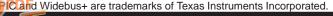
Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH32245 is characterized for operation from -40°C to 85°C.

## FUNCTION TABLE (each 8-bit section)

	(	,					
INP	UTS	OBERATION					
OE	DIR	OPERATION					
L	L	B data to A bus					
L	Н	A data to B bus					
Н_	X	Isolation					

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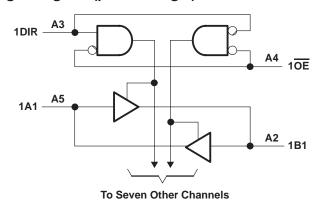


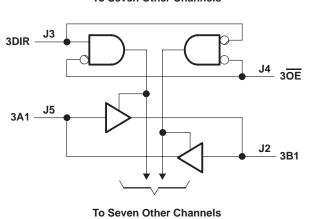
#### **GKE PACKAGE** (TOP VIEW) 1 2 3 4 5 6 Α В С 0000 D 0000 Ε 00000 F 00000 G 00000 Н 00000 J 00000 00000 Κ 00000 L 0000 M Ν 00000 Ρ 0000 00000 R Т 00000

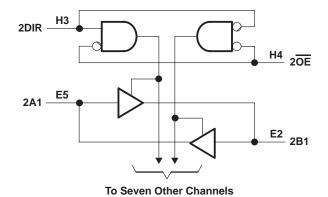
### terminal assignments

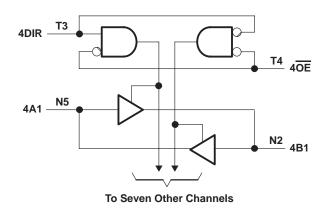
	1	2	3	4	5	6
Α	1B2	1B1	1DIR	1OE	1A1	1A2
В	1B4	1B3	GND	GND	1A3	1A4
С	1B6	1B5	VCC	Vcc	1A5	1A6
D	1B8	1B7	GND	GND	1A7	1A8
Е	2B2	2B1	GND	GND	2A1	2A2
F	2B4	2B3	VCC	VCC	2A3	2A4
G	2B6	2B5	GND	GND	2A5	2A6
Н	2B8	2B7	2DIR	2OE	2A7	2A8
J	3B2	3B1	3DIR	3OE	3A1	3A2
K	3B4	3B3	GND	GND	3A3	3A4
L	3B6	3B5	Vcc	Vcc	3A5	3A6
M	3B8	3B7	GND	GND	3A7	3A8
N	4B2	4B1	GND	GND	4A1	4A2
Р	4B4	4B3	VCC	VCC	4A3	4A4
R	4B6	4B5	GND	GND	4A5	4A6
Т	4B7	4B8	4DIR	4OE	4A8	4A7

### logic diagram (positive logic)











## SN74ALVCH32245 32-BIT BUS TRANSCEIVER WITH 3-STATE OUTPUTS

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### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V <sub>CC</sub>	
Input voltage range, V <sub>I</sub> : Except I/O ports (see Note 1)	
I/O ports (see Notes 1 and 2)	0.5 V to V <sub>CC</sub> + 0.5 V
Output-voltage range, VO (see Notes 1 and 2)	0.5 V to V <sub>CC</sub> + 0.5 V
Input clamp current, $I_{IK}$ ( $V_I < 0$ )	
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0)	−50 mA
Continuous output current, IO	±50 mA
Continuous current through each V <sub>CC</sub> or GND	±100 mA
Package thermal impedance, θ <sub>JA</sub> (see Note 3)	40°C/W
Storage temperature range, T <sub>stg</sub>	—65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.

- 2. This value is limited to 4.6 V maximum.
- 3. The package thermal impedance is calculated in accordance with JESD 51.

#### recommended operating conditions (see Note 4)

			MIN	MAX	UNIT	
Vcc	Supply voltage		1.65	3.6	V	
		$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	0.65 × V <sub>CC</sub>			
$V_{IH}$	High-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7		V	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2			
		$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$		$0.35 \times V_{CC}$		
VIL	Low-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		0.7	V	
V <sub>IL</sub> V <sub>I</sub> VO	V <sub>CC</sub> = 2.7 V			0.8		
٧ı	Input voltage		0	Vcc	V	
٧o	Output voltage		0	Vcc	V	
		V <sub>CC</sub> = 1.65 V		-4		
	High-level output current	V <sub>CC</sub> = 2.3 V		-8	mA	
ЮН		V <sub>CC</sub> = 2.7 V		-12	IIIA	
VIH		V <sub>CC</sub> = 3 V		-24		
		V <sub>CC</sub> = 1.65 V		4		
	Lour loval output ourrent	V <sub>CC</sub> = 2.3 V		8	mA	
IOL	Low-level output current	V <sub>CC</sub> = 2.7 V		12	IIIA	
	V <sub>CC</sub> = 3 V			24		
Δt/Δν	Input transition rise or fall rate			10	ns/V	
T <sub>A</sub>	Operating free-air temperature		-40	85	°C	

NOTE 4: All unused control inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



### SN74ALVCH32245 32-BIT BUS TRANSCEIVER WITH 3-STATE OUTPUTS

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## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	vcc	MIN	TYP <sup>†</sup>	MAX	UNIT		
	$I_{OH} = -100  \mu A$	1.65 V to 3.6 V	VCC-0	.2				
	I <sub>OH</sub> = -4 mA	1.65 V	1.2					
Vari	I <sub>OH</sub> = -8 mA	2.3 V	1.7			٧		
VOH	I <sub>OH</sub> = -12 mA	2.7 V	2.2			V		
	10H = -12 111A	3 V	2.4					
	$I_{OH} = -24 \text{ mA}$	3 V	2.2					
	I <sub>OL</sub> = 100 μA	1.65 V to 3.6 V			0.2			
	I <sub>OL</sub> = 4 mA	1.65 V			0.45			
V <sub>OL</sub>	I <sub>OL</sub> = 8 mA	2.3 V			0.7	V		
	I <sub>OL</sub> = 12 mA	2.7 V			0.4			
	I <sub>OL</sub> = 24 mA	3 V			0.55			
lį	$V_I = V_{CC}$ or GND	3.6 V			±5	μΑ		
	V <sub>I</sub> = 0.58 V	1.65 V	25					
	V <sub>I</sub> = 1.07 V	1.65 V	-25					
	V <sub>I</sub> = 0.7 ∨	2.3 V	45					
II(hold)	V <sub>I</sub> = 1.7 V	2.3 V	-45			μΑ		
	V <sub>I</sub> = 0.8 V	3 V	75					
	V <sub>I</sub> = 2 V	3 V	-75					
	$V_{I} = 0 \text{ to } 3.6 \text{ V}^{\ddagger}$	3.6 V	3.6 V ±50					
loz§	$V_O = V_{CC}$ or GND	3.6 V			±10	μΑ		
ICC	$V_I = V_{CC}$ or GND, $I_O = 0$	3.6 V			40	μΑ		
ΔlCC	One input at $V_{CC}$ – 0.6 V, Other inputs at $V_{CC}$ or GND	3 V to 3.6 V			750	μΑ		
C <sub>i</sub> Control inputs	V <sub>I</sub> = V <sub>CC</sub> or GND	3.3 V		4		pF		
C <sub>io</sub> A or B ports	$V_O = V_{CC}$ or GND	3.3 V		8		pF		

<sup>&</sup>lt;sup>†</sup> All typical values are at  $V_{CC}$  = 3.3 V,  $T_A$  = 25°C.

## switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub> = 1.8 V ± 0.15 V		V <sub>CC</sub> = 2.5 V ± 0.2 V		V <sub>CC</sub> = 2.7 V		V <sub>CC</sub> = 3.3 V ± 0.3 V		UNIT
	(1141 01)	(0011 01)	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t <sub>pd</sub>	A or B	B or A	¶	¶	1	3.7		3.6	1	3	ns
t <sub>en</sub>	ŌĒ	A or B	¶	¶	1	5.7		5.4	1	4.4	ns
<sup>t</sup> dis	ŌĒ	A or B	¶	¶	1	5.2		4.6	1	4.1	ns

 $<sup>\</sup>P$  This information was not available at the time of publication.

### operating characteristics, $T_A = 25^{\circ} C$

PARAMETER			TEST CONDITIONS		V <sub>CC</sub> = 1.8 V	V <sub>CC</sub> = 2.5 V	V <sub>CC</sub> = 3.3 V	UNIT
			TEST CONDITIO	113	TYP	TYP	TYP	ONIT
<u> </u>	Power dissipation	Outputs enabled	C: - 50 pF f - 1	0 MHz	¶	22	29	pF
C <sub>pd</sub>	capacitance	Outputs disabled	$C_L = 50 \text{ pF},  f = 10$	U IVIMZ	¶	4	5	pΓ

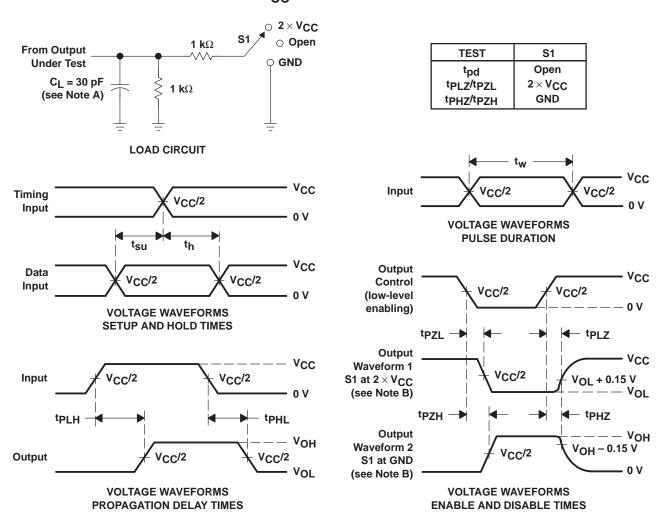
This information was not available at the time of publication.



<sup>‡</sup> This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

<sup>§</sup> For I/O ports, the parameter IOZ includes the input leakage current.

# PARAMETER MEASUREMENT INFORMATION $V_{CC} = 1.8 \text{ V} \pm 0.15 \text{ V}$



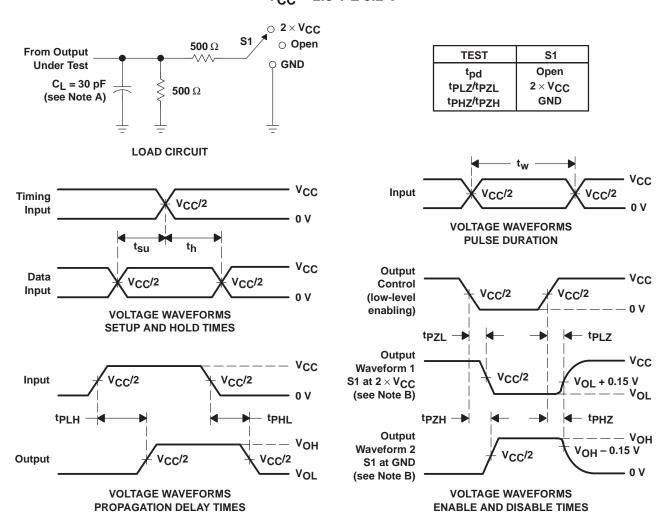
NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz, Z<sub>Q</sub> = 50  $\Omega$ ,  $t_f \leq$  2 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLz and tpHz are the same as tdis.
- F. tpZL and tpZH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



# PARAMETER MEASUREMENT INFORMATION $V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$

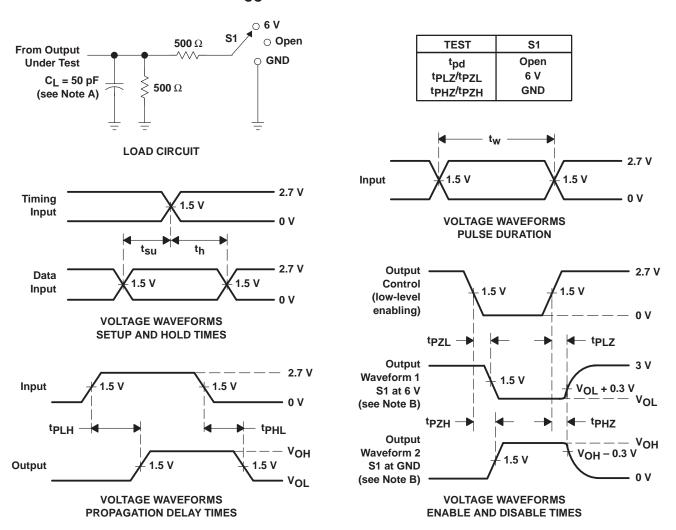


NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_{\Omega}$  = 50  $\Omega$ ,  $t_r \leq$  2 ns,  $t_f \leq$  2 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLz and tpHz are the same as tdis.
- F. t<sub>PZL</sub> and t<sub>PZH</sub> are the same as t<sub>en</sub>.
- G. tpLH and tpHL are the same as tpd.

Figure 2. Load Circuit and Voltage Waveforms

# PARAMETER MEASUREMENT INFORMATION $V_{CC}$ = 2.7 V AND 3.3 V $\pm$ 0.3 V



NOTES: A.  $C_L$  includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_Q = 50 \Omega$ ,  $t_f \leq 2.5 \text{ ns.}$
- D. The outputs are measured one at a time with one transition per measurement.
- E.  $t_{PLZ}$  and  $t_{PHZ}$  are the same as  $t_{dis}$ .
- F. tpzL and tpzH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 3. Load Circuit and Voltage Waveforms



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